

**Search Notes**

Application/Control No.

09/577,932

Examiner

Chris C. Chu

Applicant(s)/Patent under  
Reexamination

MARUYAMA ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
257	797, 786, 737 & 738	2/14/2005	C.C.

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB; and USOCR;	2/14/2005	C.C.